Testbeam with 3D Silicon Pixel Detectors for Forward Physics

PRELIMINARY Results

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IFAE Barcelona

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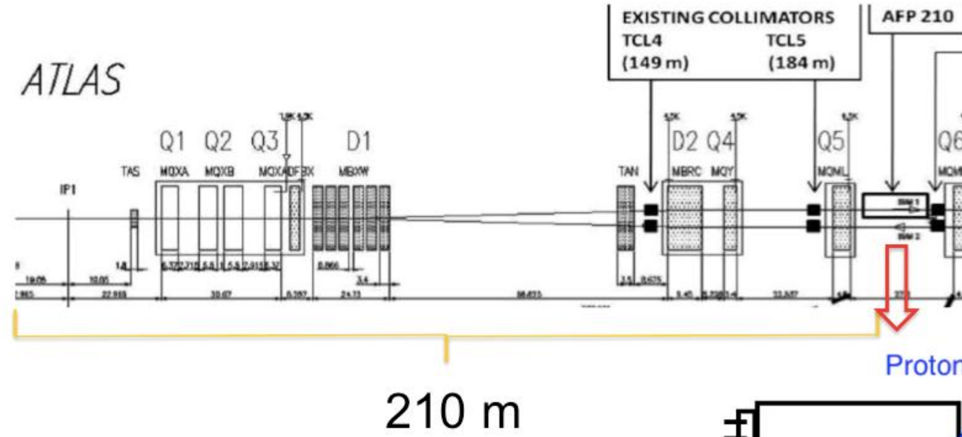
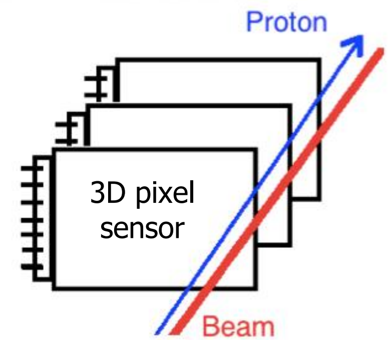
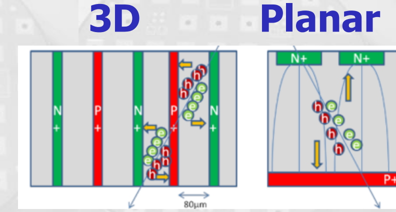
Introduction

- Atlas Forward Physics (AFP)
  - Diffractive physics: protons leave pp interaction intact
    → very forward protons
  - Combination of
    3D pixel tracker and fast timing detectors for pile-up removal
  - Detectors close to the beam (2-3 mm) for good acceptance
- → Requirements:
  - Slim edge of side facing beam: ~100-200 µm
  - Highly non-uniform irradiation
- Status of the proposal
  - AFP conditionally approved for dedicated low-lumi runs
  - Possible high-lumi upgrade later
  - Installation planned for end of 2015
    → second use of 3D silicon sensors in HEP experiment!

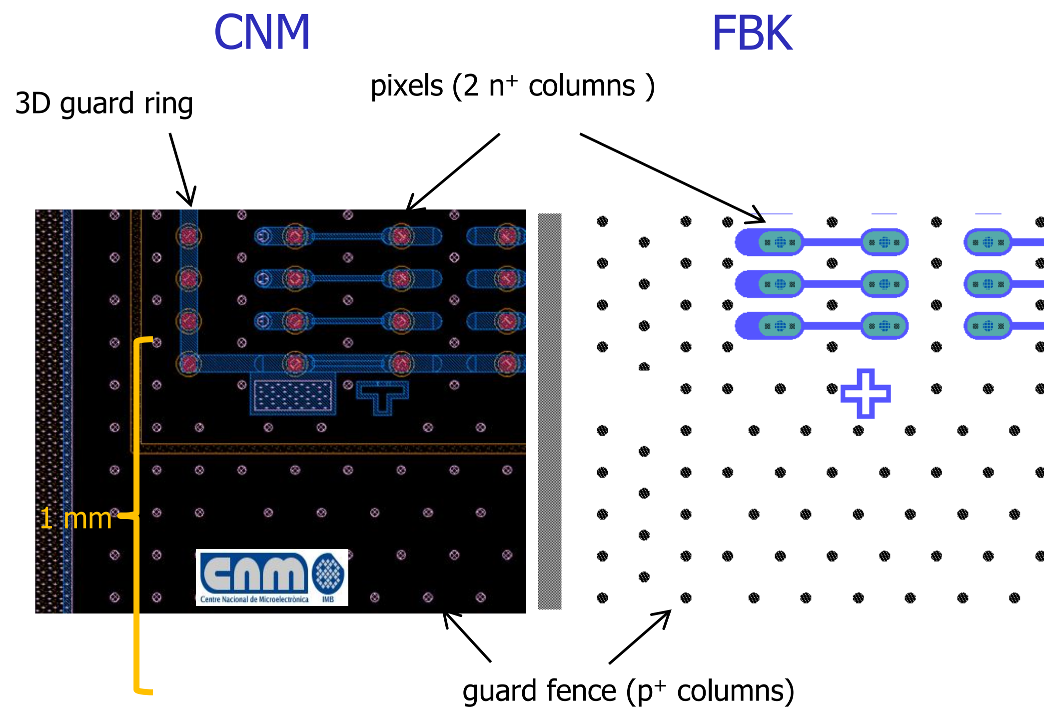




Sensors and Edge Slimming



- FE-I4 3D IBL sensors (CNM and FBK)
  - 336x80 pixels of 50x250 μm²
  - p-type bulk, 2 n⁺ columns per pixel
  - Edge termination:
    - CNM: 3D guard ring of n⁺ columns + p⁺ ohmic-column fence
    - FBK: p⁺ ohmic-column fence
    - Left/right already 200 μm slim edge
    - Bottom: >1 mm bias tab (not needed!)
  - IBL spares (not always best quality)



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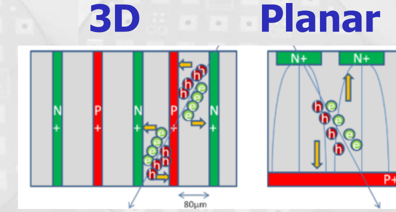

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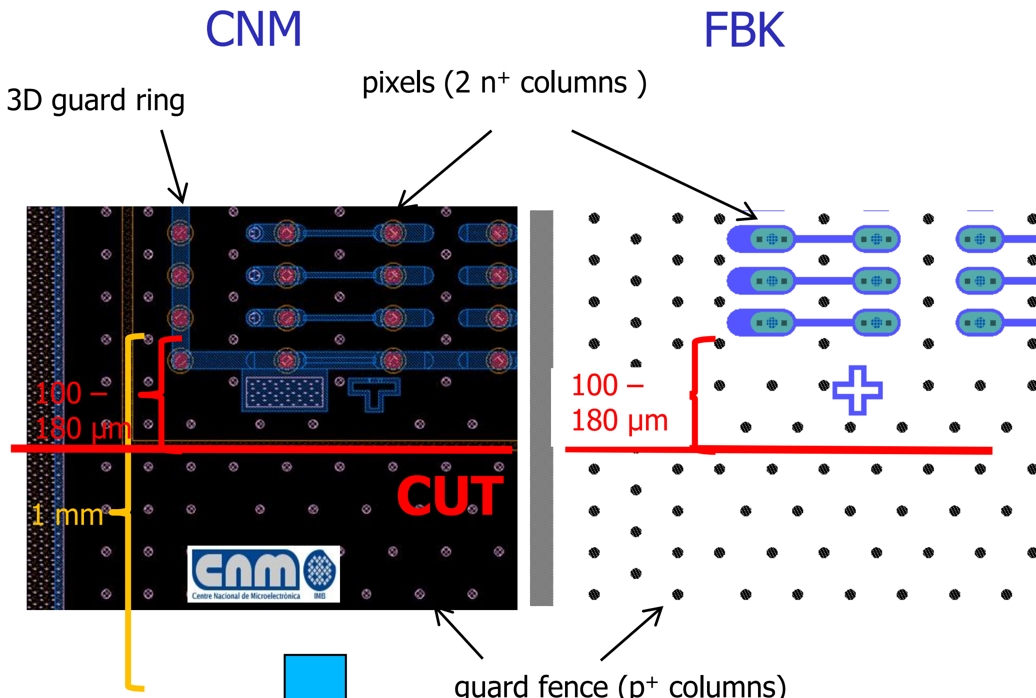
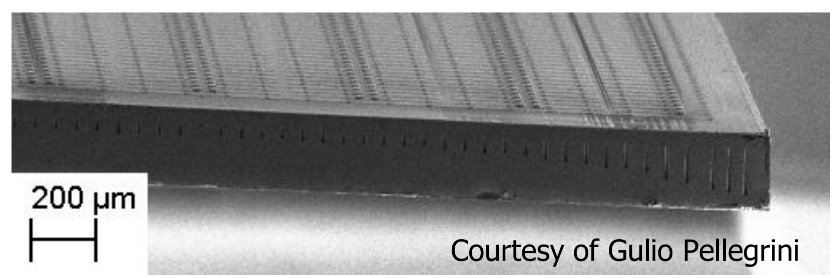


- Edge slimming:
  - Cut IBL sensors' inactive bottom edge down to 100-180 µm (FE-I4 chip: 80 µm dead region)
  - Technique here: standard diamond-saw cut

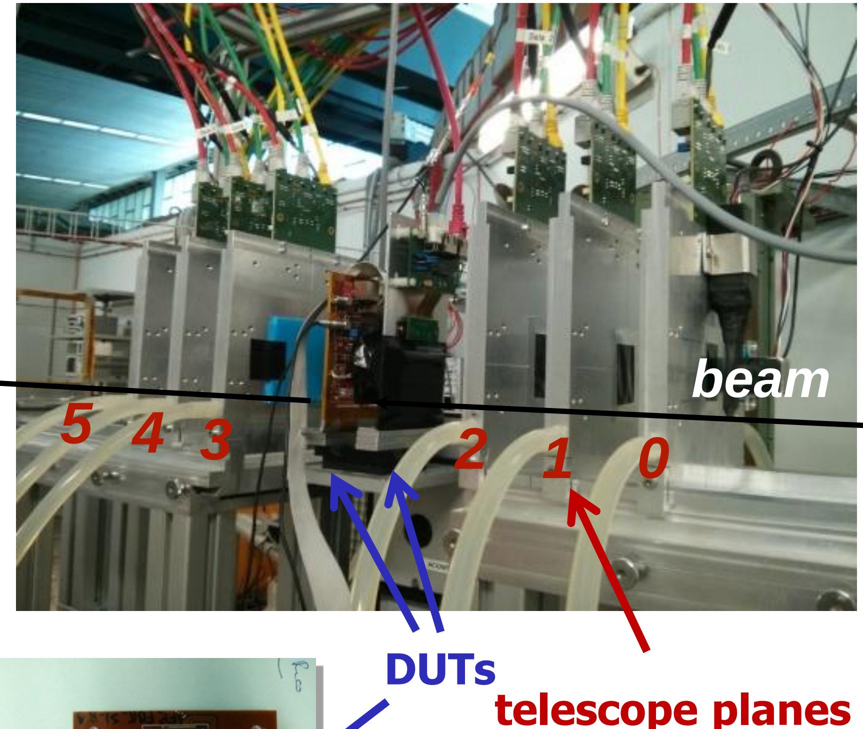


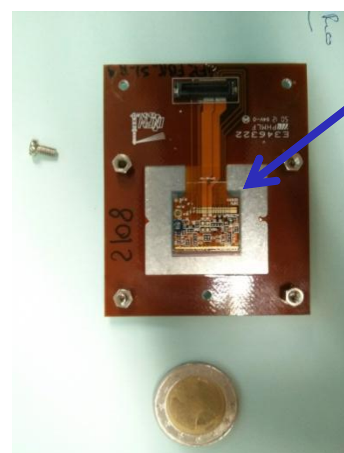
DESY Test Beam

- Check performance in test beam
  - Slim-Edge: June 2013
  - DESY 5 GeV electrons
  - Normal incidence
  - ACONITE telescope (EUDET type)
  - 2 FE-I4 DUTs (reference for each other)
    - USBpix readout + STControl

see B. Paschen's talk for details

  - EUTelescope Reco + TBMon for analysis
  - Thanks to AIDA support

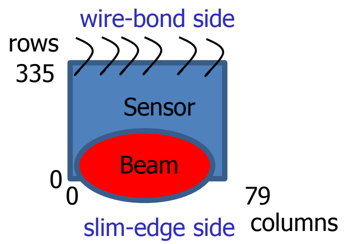




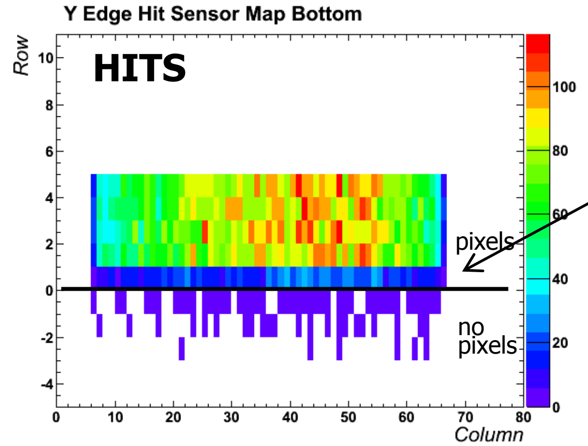
AIDA

Thanks to all test beam participants,
esp. I. Rubinskiy (DESY), D. Pohl (Bonn),
O. Korchak (Prague), Sh. Hsu (Washington),
A. Micelli (IFAE)

Slim-Edge Efficiency – Row0-Bugfix



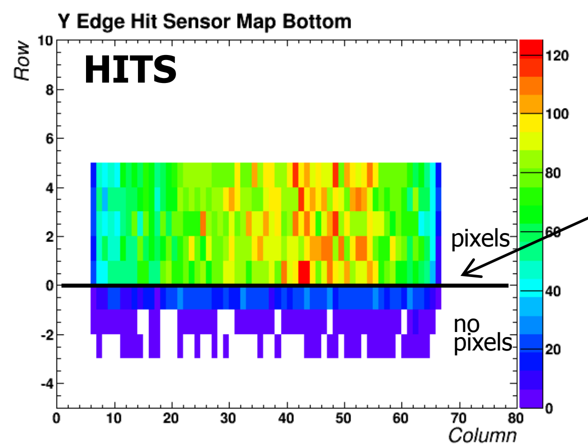
Before Bugfix:



- Observation in EUTelescope v00-08-02:
  Hit deficiency in row 0,
  leading to bad efficiency in row 0

- Bug in *EUTelAPIXClusteringProcessor.cc* (l. 554)
  - 0^{th} row excluded
  - Bug fixed with help of Igor/Hanno

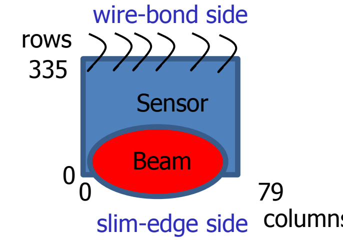
After Bugfix:

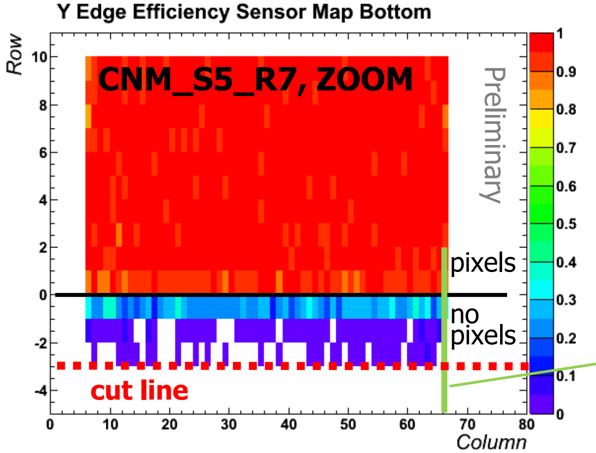


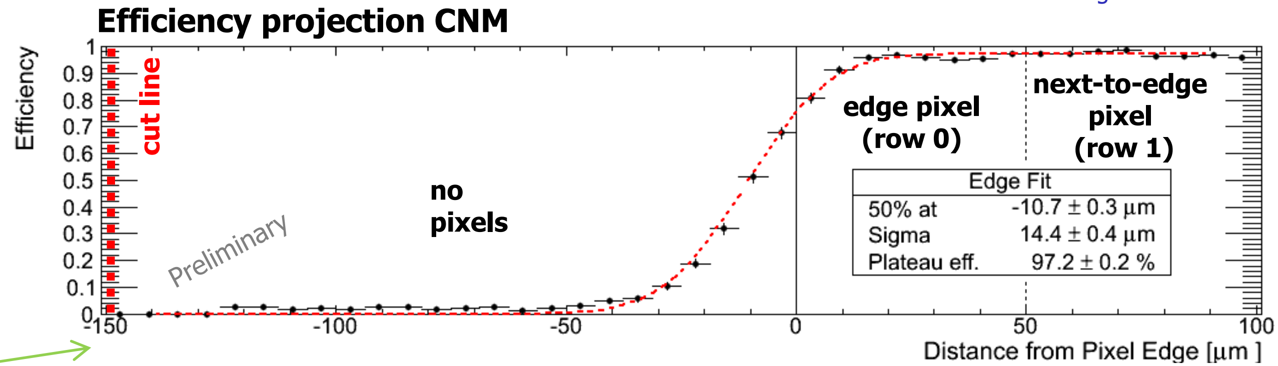
Sensor: AFP_CNM_S5_R7 (batch2a)

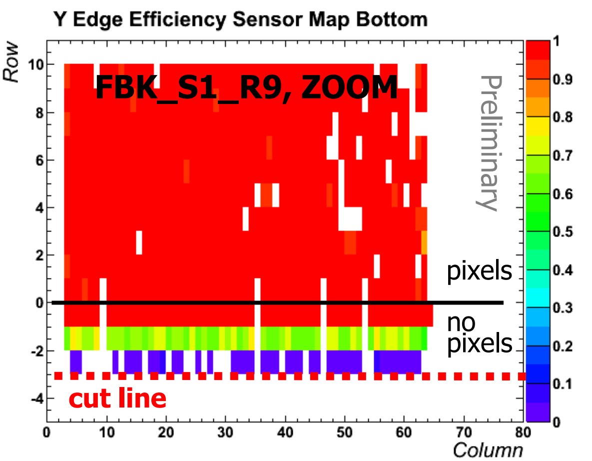
- After Bugfix (from v00-09-03 on):
  Recovery of hits in row 0
  → excellent efficiency up to the edge

Slim-Edge Efficiency

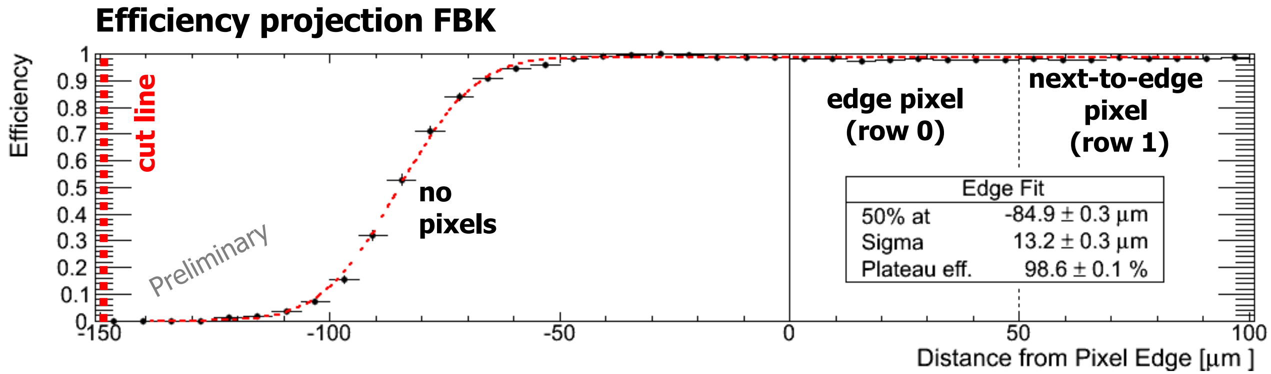








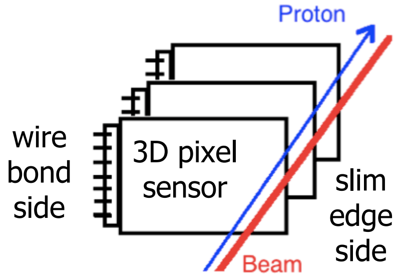
20 V bias



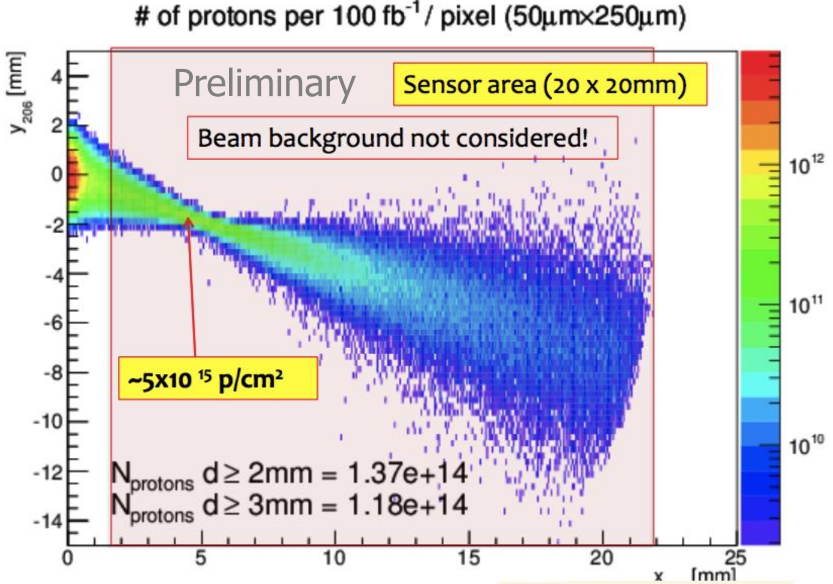
- Efficiency stable up to last pixel
- For FBK even ~80 µm beyond: Efficient edge due to absence of guard ring (but implications on resolution/alignment if edge pixel is different)
- In both cases: AFP slim-edge requirements fulfilled (<180 µm dead area)

Radiation Hardness Requirements

- Highly non-uniform irradiation
  → high fluence gradient between neighbouring pixels
- Integrated fluence depends on run scenario
- Low-μ run scenario (approved AFP scenario for start)
  - Only dedicated runs → ~100 pb^{-1}
  - Fluence peak: $5x10^{12}$ p/cm^2 (~7 TeV p)
    → should be manageable
- High-μ run scenario (possible future scenario)
  - In the beam for large parts of run 2 → ~100 fb^{-1}
  - Fluence peak: $5x10^{15}$ p/cm^2 (~7 TeV p)
    → studied in the following



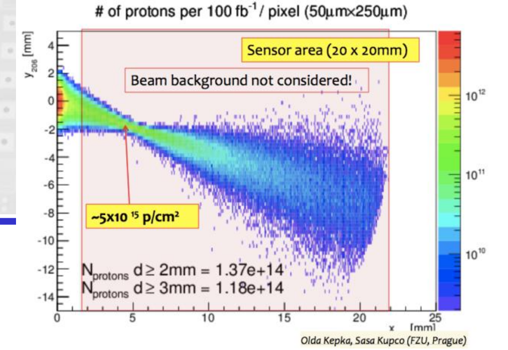
Estimated Fluence for high-μ run:



Olda Kepka, Sasa Kupco (FZU, Prague)

- To check:
  Can detector be operated to give high efficiency in all regions?
  - Unirradiated: Low V_{BD} → $V<V_{BD}$ needed
  - Irradiated region: High V needed ($V>V_{dep,irr}$, E field)

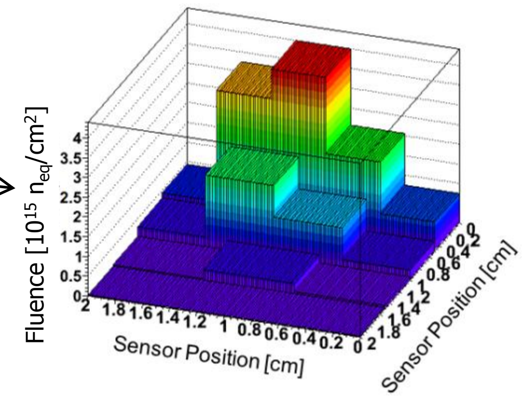
Non-Uniform Irradiation



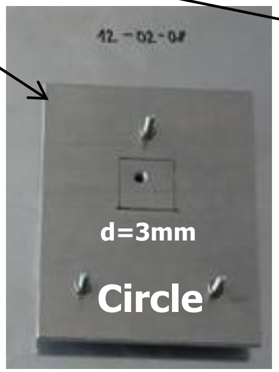
- No 7 TeV irradiation facility available yet…
  - Radiation damage of 7 TeV p not yet calculated. Similar to GeV p? Maybe should be studied? (important for all forward exp.)

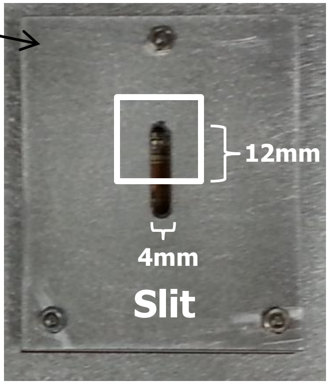
  → Here: Proof-of-principle tests at usual irrad. facilities with lower p energy
- First test beam study in 2012 with focussed CERN-PS 23 GeV irradiation
  see A. Micelli, 21st RD50 workshop Nov 2012; S. Grinstein, 8th Trento workshop 2013
- But fluence spread was large
- Another irradiation with more localised fluence:
  23 MeV protons (KIT) through hole in Al plate (5 mm thick)

Fluence map of CERN-PS irradiation:



Al shields at Karlsruhe:



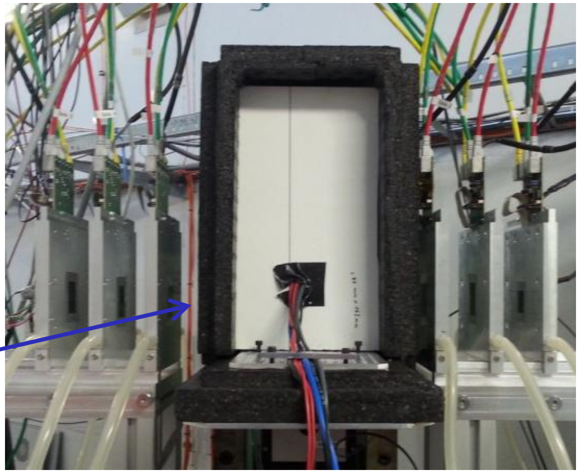


Thanks to Felix Bögelspacher (KIT) for irradiation
and Petr Sicho (CERN) for help

Non-Uniform Irradiation	PS 23 GeV p Focussed beam	KIT 23 MeV p Hole (circle)	KIT 23 MeV p Hole (slit)	
Φ [10^{15} n_{eq}/cm^2]	4.0 (max)	1.8	3.3	3.6
Sample	CNM 57	FBK 12_02_08	CNM S5-R7	CNM S3-R5
Edge	Regular	Regular	Slimmed	Slimmed

Testbeam of Irradiated Devices

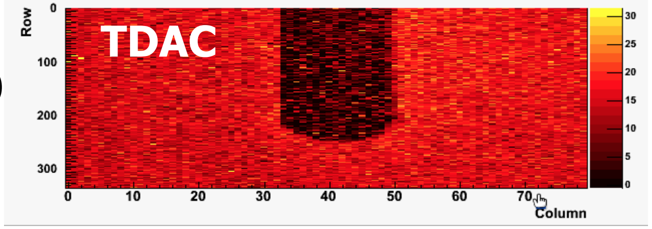
- CERN for PS irr. device
  - August 2013 (120 GeV pions)
- DESY for KIT irr. devices
  - July 2013 (5 GeV e)
  - Jan 2014 (4 GeV e -> higher rate)
- Usually normal incidence
- Cooling with dry ice in styrofoam box



  - T ~ -30 °C measured in air (unknown at sensor; NTC minimum of -20 °C reached) -> would be nicer to have better T control and monitoring

see B. Paschen's talk for details

- Different runs at different bias voltages of irradiated sample (V limited by high I_{leak})
- Thresh. tuning of non-uniformly irrad. sample a challenge
  - Irradiated pixels prefer lower TDAC (single-pixel threshold DAC)

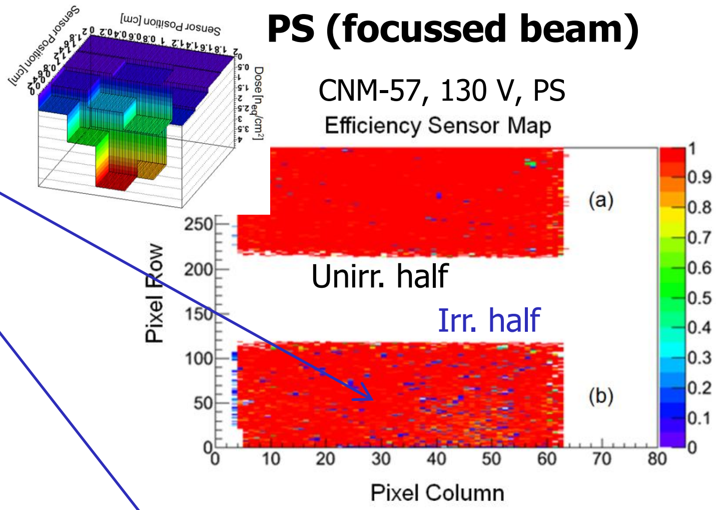


- Still partly some reconstruction missing
  - Noisy MIMOSA plane in few runs -> how to exclude? -> Would be nice to have some examples/documentation

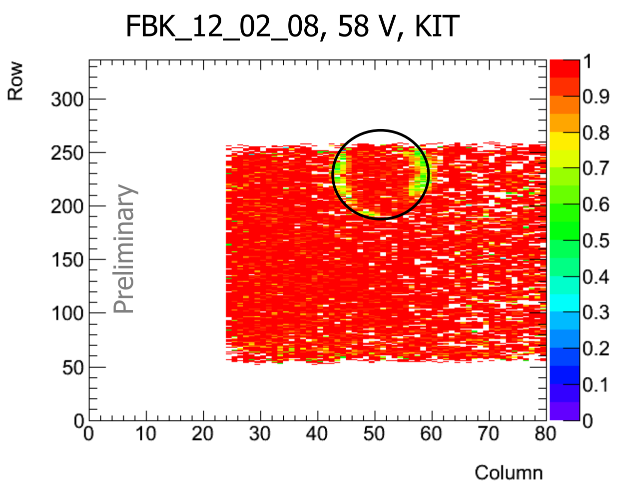
Efficiency of Irradiated Devices

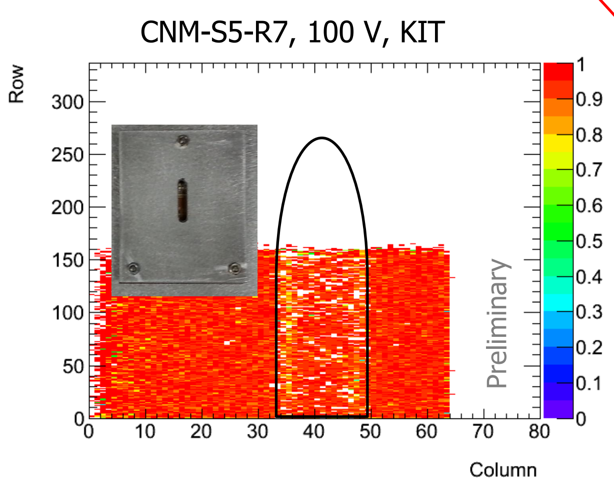
- Irradiated area (only centre for KIT) almost as efficient as unirradiated region
- Ring of lower efficiency at edge of hole at KIT
  - Not seen for focussed PS beam
  - Under investigation (see slides later)

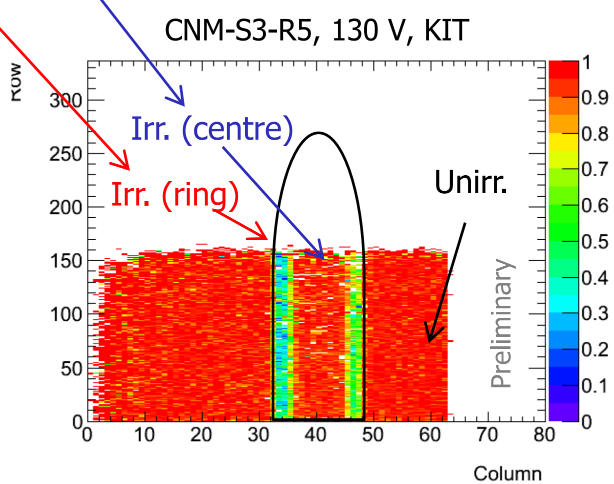
PS (focussed beam)



KIT (through hole)



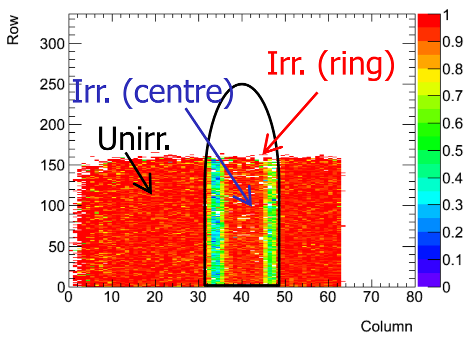




Noisy and dead pixels masked

Measurement Summary and Efficiency Results

	Non-Uniform Irradiation	Unirr. Reference	PS Focussed	KIT Hole (circ.)	KIT Hole (slit)	
Device + Irrad	Φ [10^{15} n_{eq}/cm^2]	Unirr.	4.0 (max)	1.8	3.3	3.6
	Sample	CNM 55	CNM 57	FBK 12_02_08	CNM S5-R7	CNM S3-R5
	Edge	Regular	Regular	Regular	Slimmed	Slimmed
Meas. Settings	**Threshold [ke]**	3	1.7	2	2	3
	ToT at 20 ke	10	10	~11	~5	~8
	SingleSmall Hits Rejected	No	No	No	Yes	Yes
Results	**Eff_{max}(unirr) [%]**	99	99	98	95	94
	Eff_{max}(irr,centre) [%]	-	98	97	94	93
	Eff_{max}(irr,ring) [%]	-	-	70	90	58



- Irradiated part (centre) within 1% as efficient as unirrad. part; significantly lower eff. in ring of irr. part

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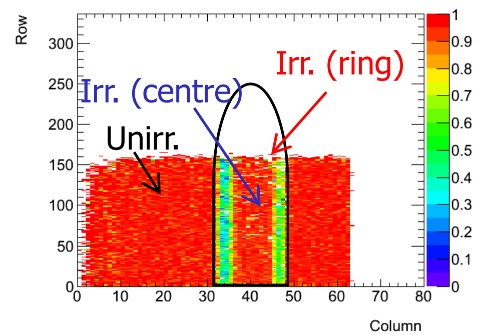
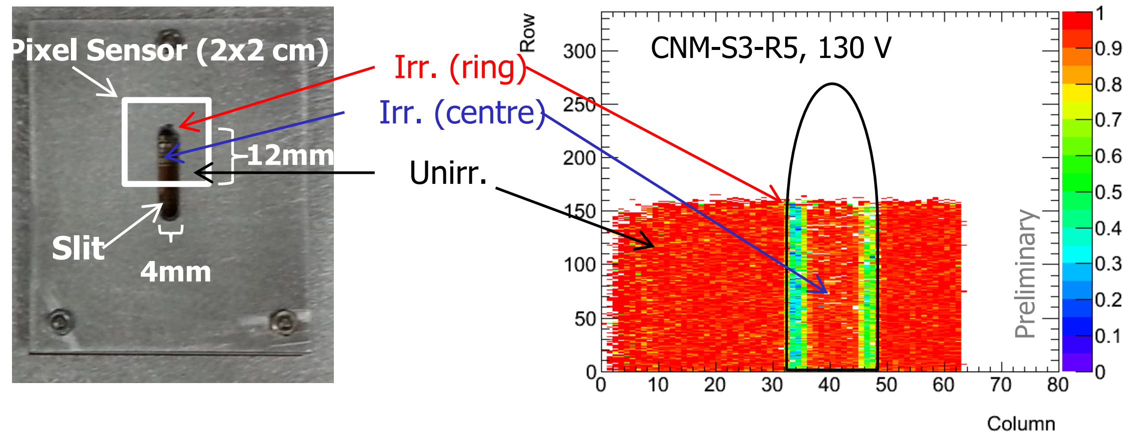


- Irradiated part (centre) within 1% as efficient as unirrad. part; significantly lower eff. in ring of irr. part
- 3-4% lower efficiency of 2 CNM devices irrad. at KIT (both unirr. and irr. area) is **artifact**!
  - Chip register HitDiscCnfg =2 (0 for other meas.) → Single small hits (ToT<3) rejected (good to avoid time-walk effects, but usually test beam analyses take all hits into account)
  - Especially large effect in combination with low ToT tuning (verified with source scans: 5-20% eff. loss possible)
    -> central documentation with WARNINGs would be useful
- Despite partly unfavourable settings: ≥ 93% in irr. part (centre) achieved (≥ 97% for favourable settings)

Investigation of Low-Efficiency Ring

5 mm Al shields:

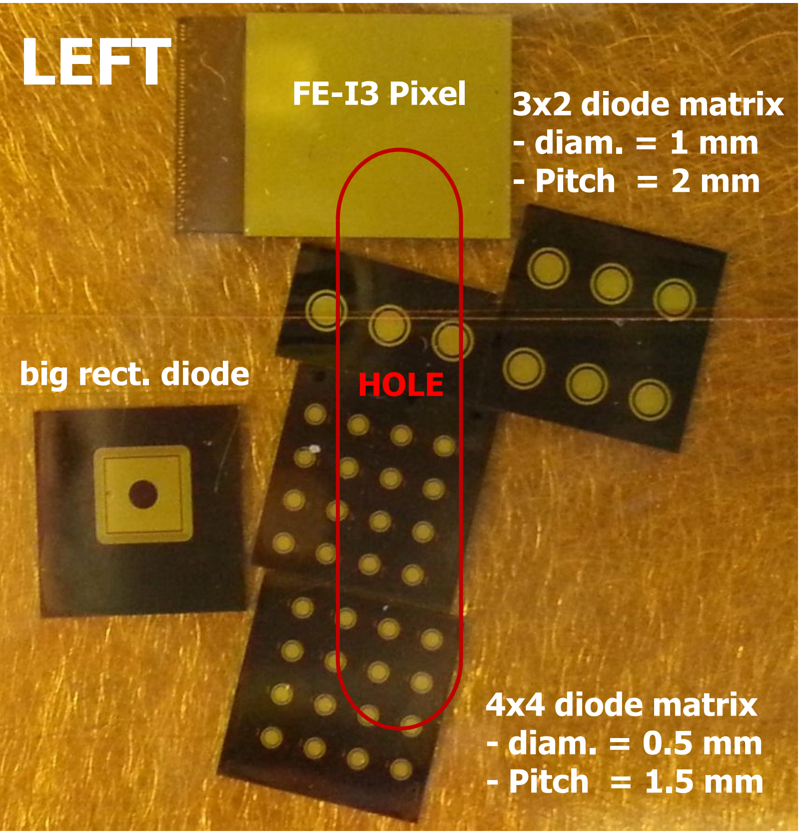
Pixel-Sensor Efficiency Map

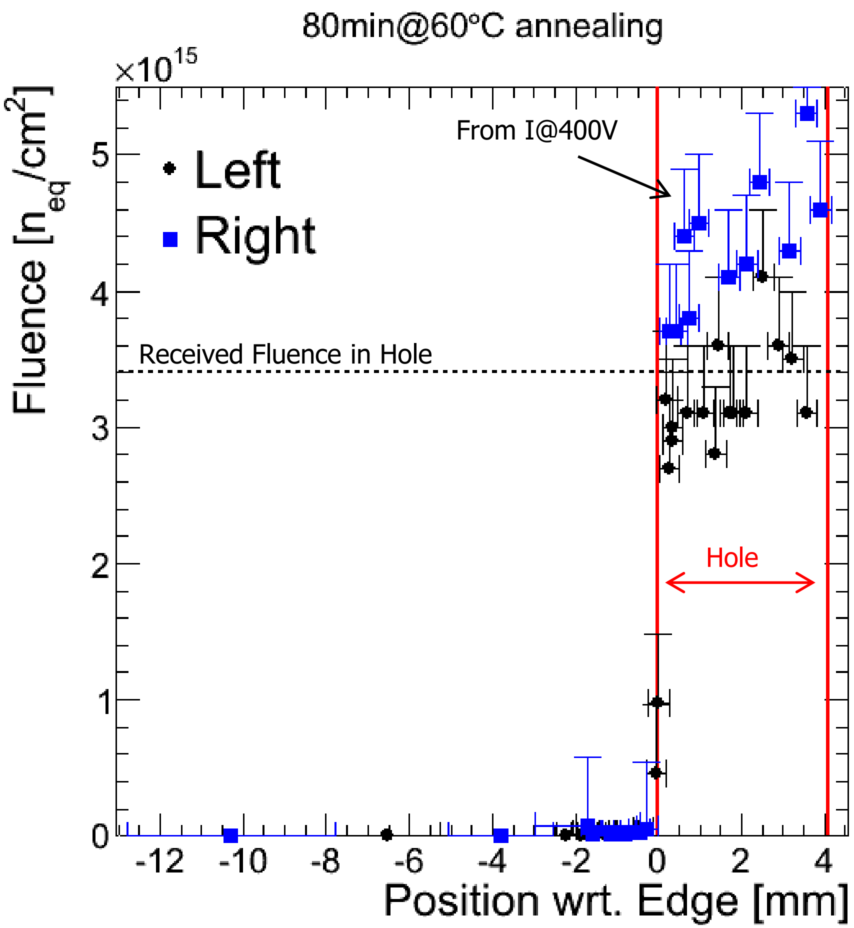


- Effect of irradiation method with Al shield (possibly higher effective fluence)?
  - Scattering of p at edge of Al shield → loose energy → much more damaging
- Or real effect of sharply non-uniformly irradiated devices?
  - Sensor effect?
    - Transition region between highly irradiated Si and unirradiated Si → huge gradient of defect density and current → maybe leads to lower el. field?
  - Chip effect?

Position-Resolved Dosimetry from IV

$$\Delta I(\Phi_{eq}) = \alpha \Phi_{eq} V$$

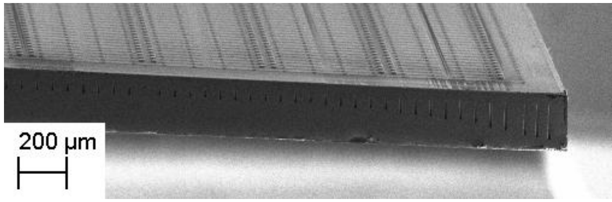




- Optimally done on non-uniformly irr. FE-I4 -> Does anyone know how MONLEAK scan works?
- New irradiation with diode arrays under same slit-like Al masks (left+right) at KIT (3.4×10^{15} n_{eq}/cm^2)
- No significant difference between centre and edge of irr. region; consistent with received fluence
- Substantial fluence ($\sim 10^{12} - 10^{13}$ cm^{-2}) also under Al mask; higher the closer to the hole

Conclusions

- Slim-edge and non-uniformly irradiated 3D AFP sensors studied in test beams
  - Inactive pixel-sensor region highly reduced (to 100-180 μm) without impact on efficiency
    - Without guard ring even efficient beyond last pixel
  - High efficiency achievable in centre of irradiated part at high-μ fluence (100 fb^{-1})
    - ≥97% for all devices with optimal tuning and parameter setting
  - Low efficiency at edge of irradiated hole
    - Position-resolved dosimetry shows no hint of higher fluence at edge (at least not from I_{leak})
  - For approved low-μ run (100 pb^{-1}): 3 orders of magnitude less → relaxed conditions

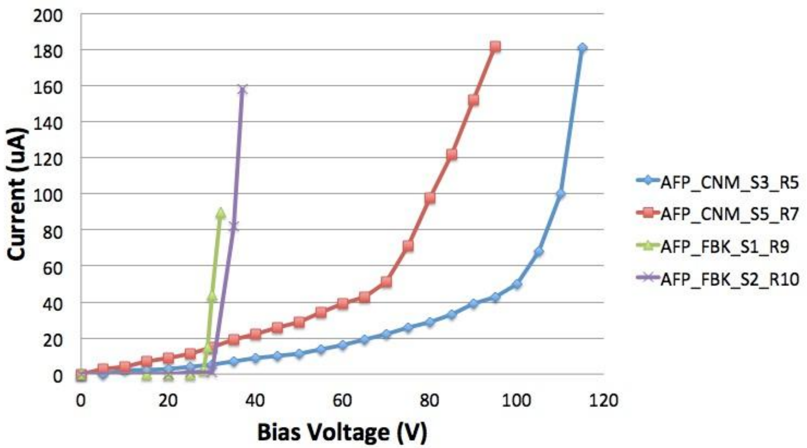


- Outlook:
  - Charge-collection measurements on dosimetry-diodes
  - Simulation of non-uniformly irradiated sensor
  - AFP integration testbeam (tracking+timing) in November at SPS, possibly with own FE-I4 telescope (see I. Lopez' talk)

BACKUP

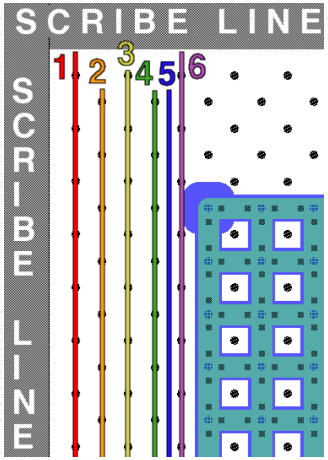
Current and Noise

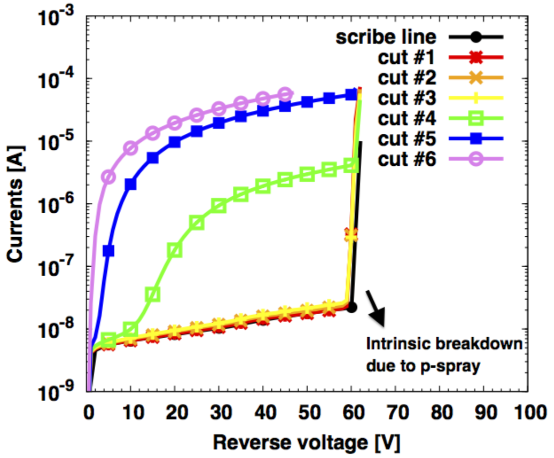
IV of sensors used here (2 FBK, 2 CNM):
normal for used sensor-quality class



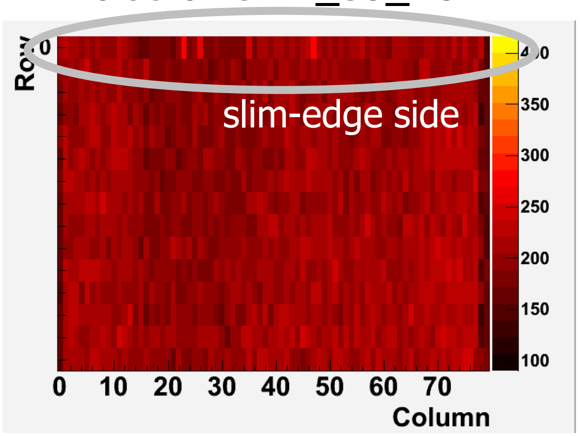
Previous study on FBK sensors:
IV unaffected up to 100 µm cut line

M. Povoli et al., JINST 7 (2012) C01015





Noise of CNM_S3_R5

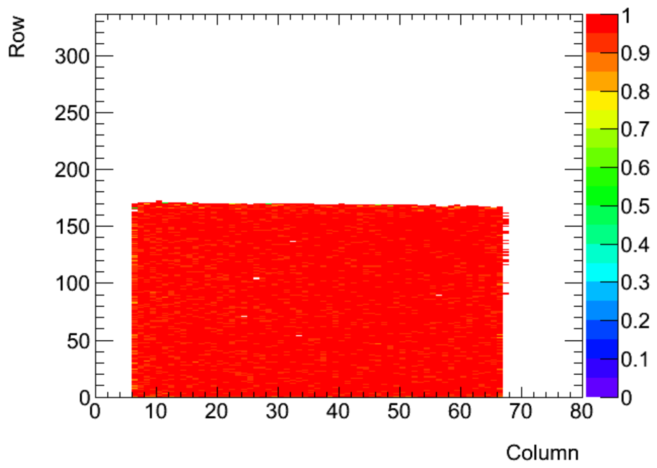


- No anomalous current and noise after edge-slimming to 100-180 µm

Efficiency of Slim-Edge Sensors in Test Beam

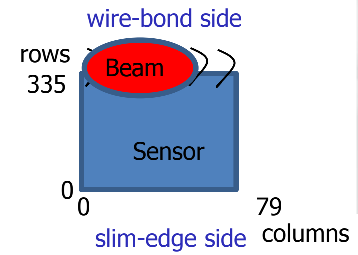
- DESY II Test beam: 4 or 5 GeV electrons
- ACONITE telescope (EUDET type)
- Normal incidence
- 1 reference IBL sensor,
  4 slimmed-edge AFP sensors
- Average efficiency after slimming (97-99%) comparable to IBL reference
  → what about edges?

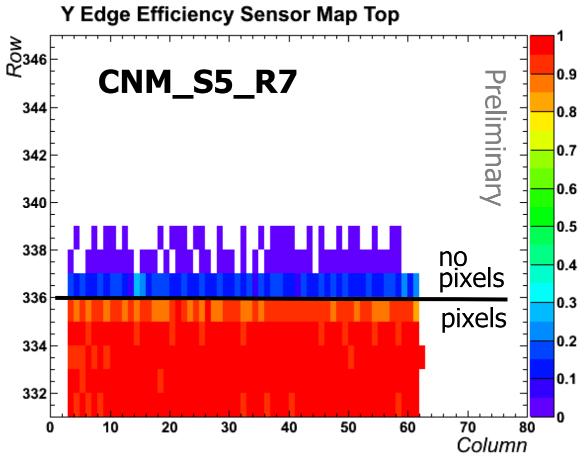
Thanks to all test beam participants, esp. I. Rubinskiy (DESY), D. Pohl (Bonn), O. Korchak (Prague), Sh. Hsu (Washington)

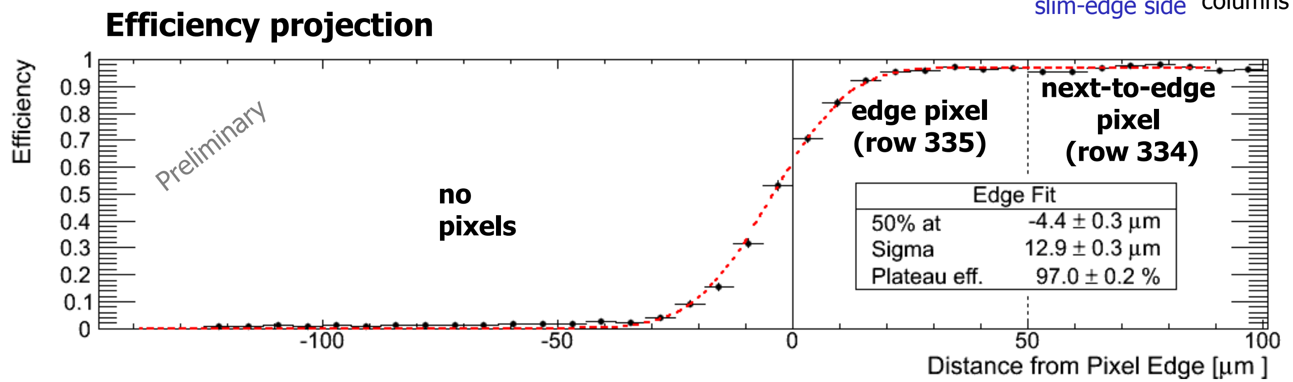


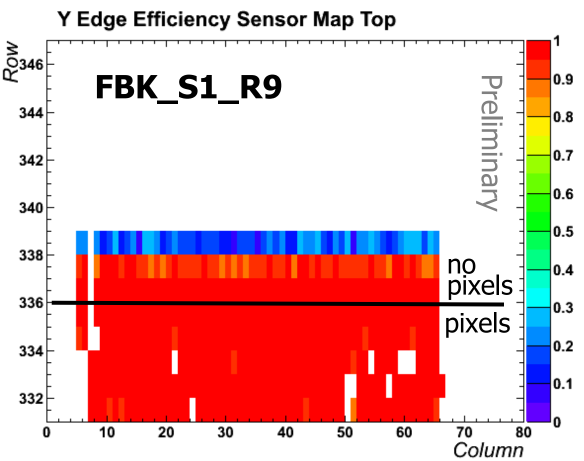
	DUTs				
Sample	CNM-55 (Refer.)	CNM_S3_R5	FBK_S5_R10	CNM_S5_R7	FBK_S1_R9
Edge	Regular	Slimmed	Slimmed	Slimmed	Slimmed
Bias [V]	30	30	20	30	20
Threshold [ke]	2.8	1.9	2.0	2.0	2.0
Efficiency	98-99%	98.3%	98.6%	96.9%	98.0%

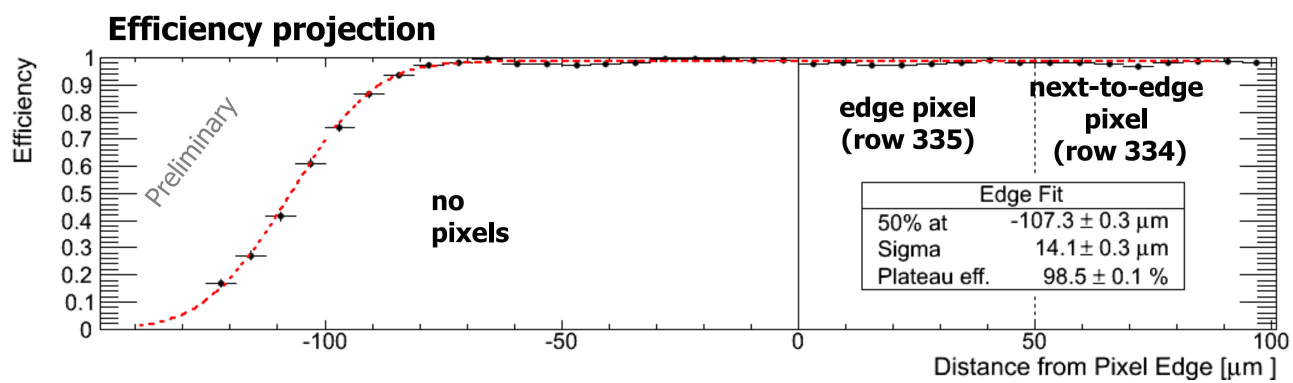
Regular Unslimmed Edge (Top Side)





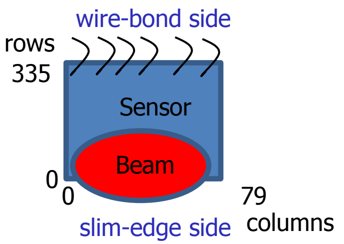


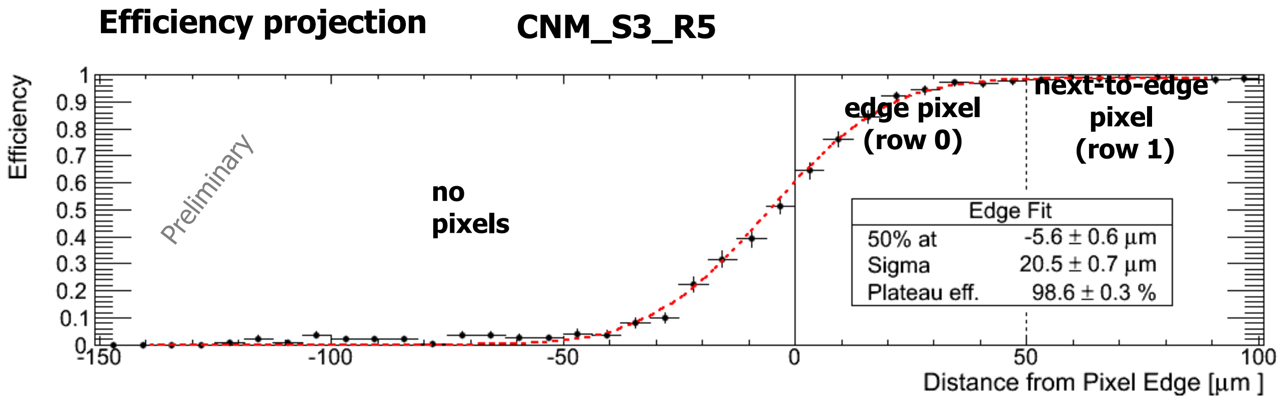


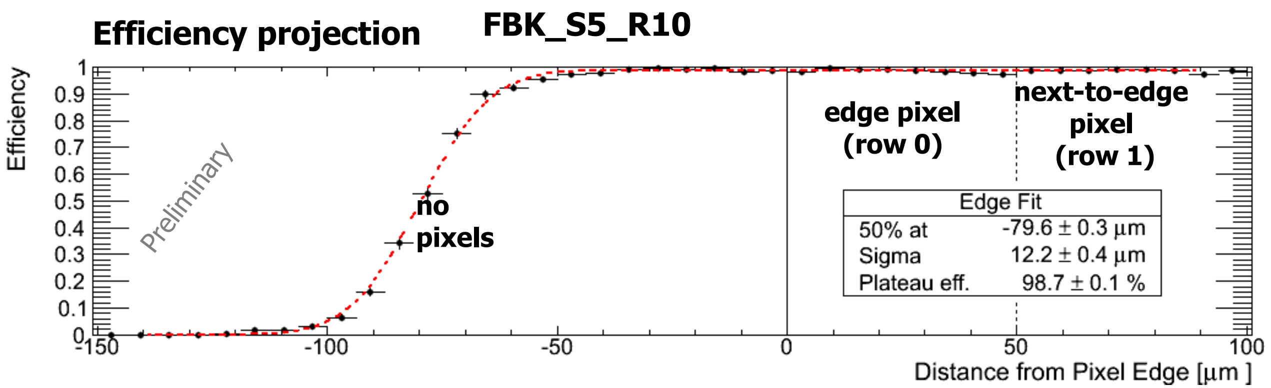


- Efficiency stable up to last pixel
  - Smearing due to beam telescope resolution
  - For FBK even ~100 µm beyond (active edge due to absence of guard ring); a bit noisy/hot pixels → masked

Slim Edge (Bottom Side) Other devices



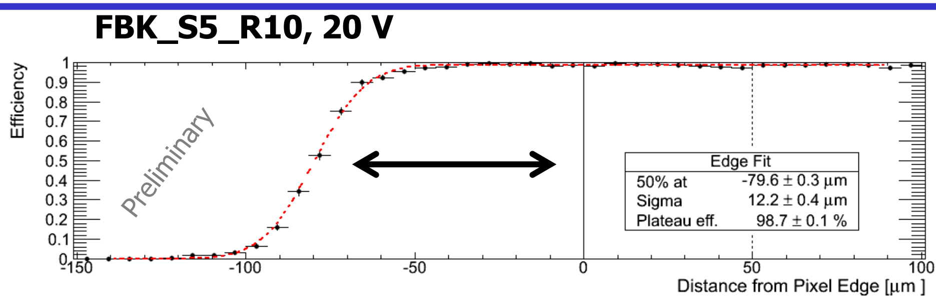


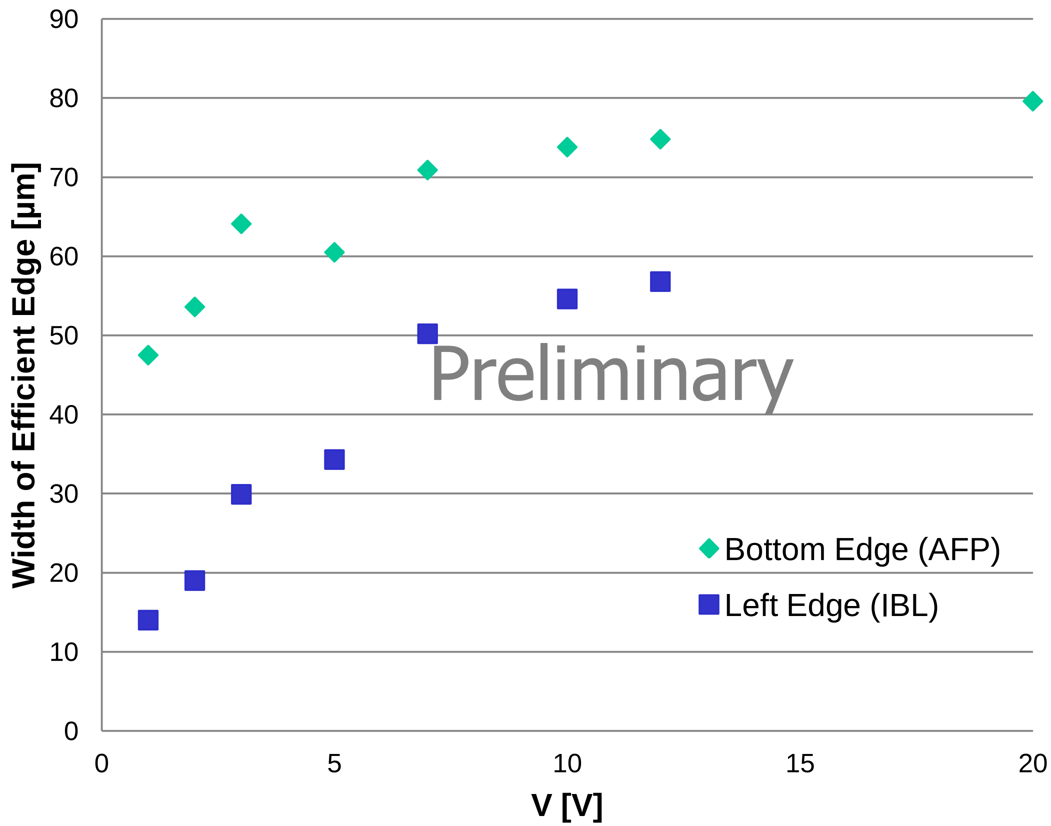


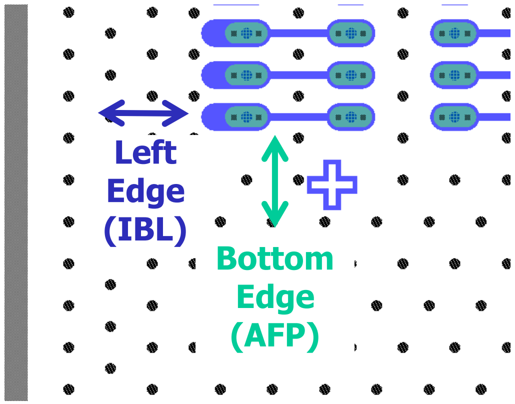
- Efficiency stable up to last pixel
  - For FBK even ~85 µm beyond (active edge due to absence of guard ring); a bit noisy/hot pixels → masked

→ same behaviour as for non-slimmed edge!

Development of Efficient Edge in FBK Sensor with Voltage







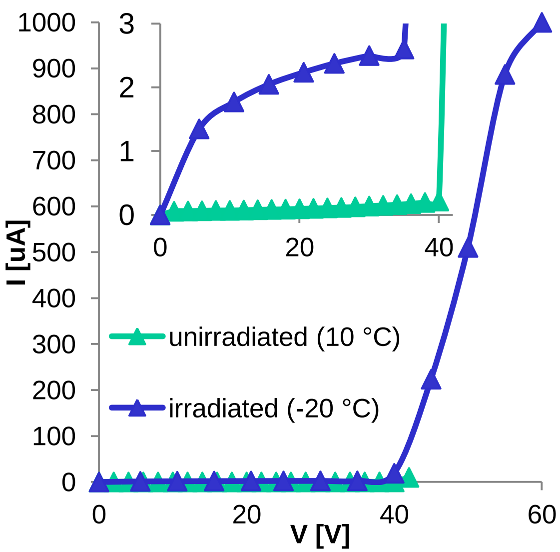
- Width of efficient edge increases with voltage (depletion zone increases)
- Saturation between first and second guard line beyond last pixel
- Bottom edge has larger width of efficient edge than left edge

Electrical Characteristics

- Not optimal sensors from beginning (IBL spares)
  - Merged/disconnected bump bonds, partly low V_{BD}

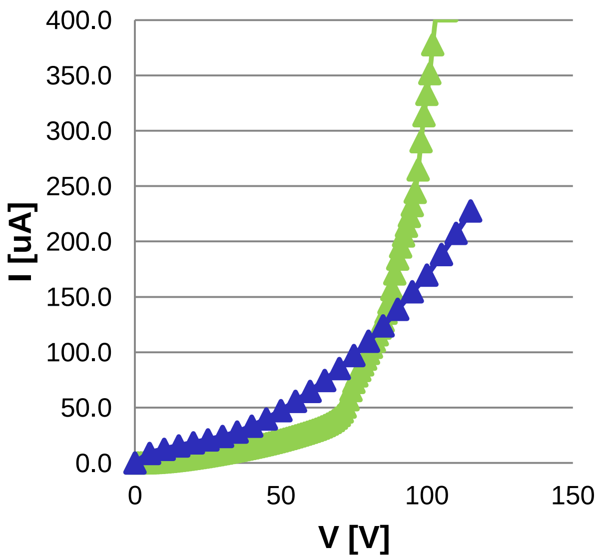
FBK_12_02_08

- V_{BD} ~ 40 V before and after irrad.
- Able to bias up to 58 V



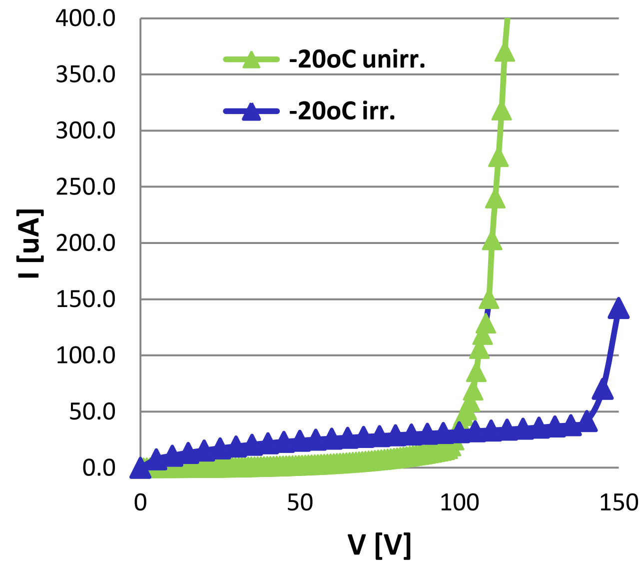
CNM_S5_R7

- Soft BD
- Lower I after irr. at high V



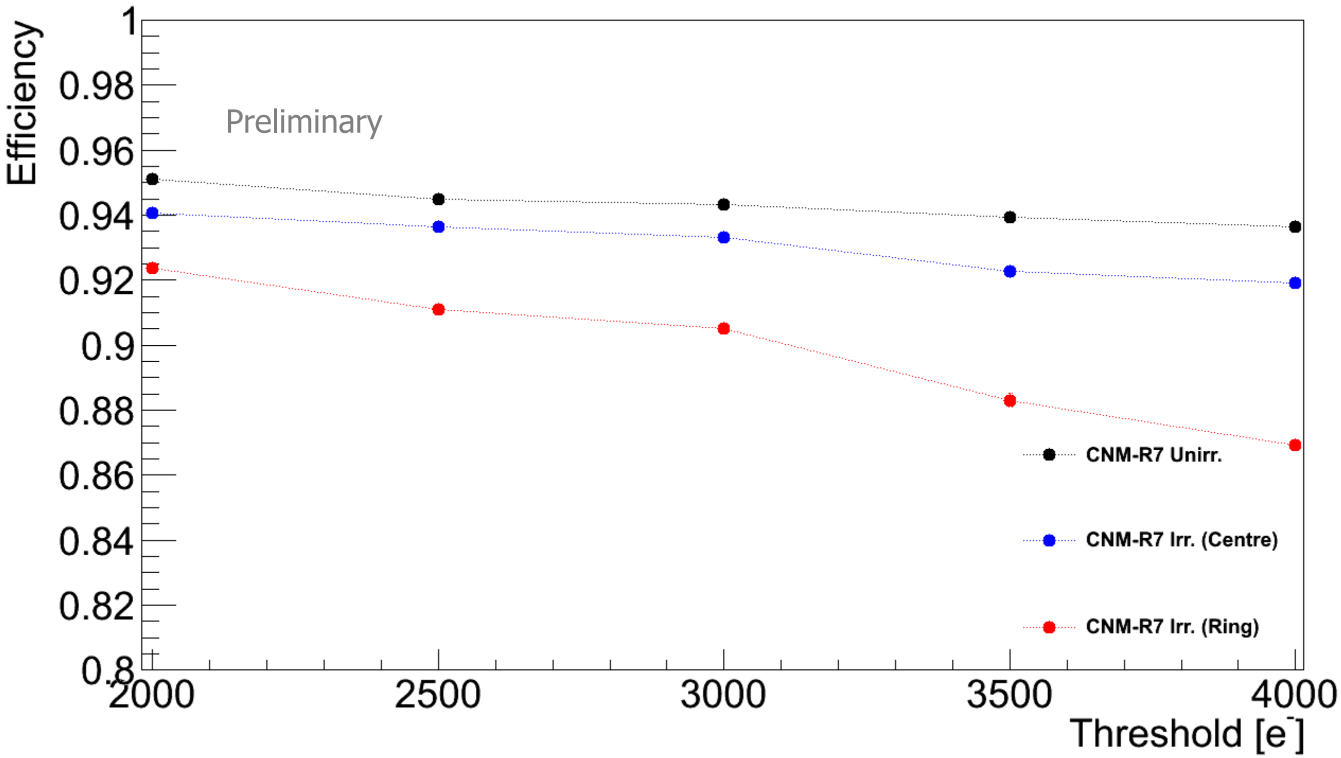
CNM_S3_R5

- Shift of V_{BD} to higher V
- Lower I after irr. at high V



Efficiency vs. Threshold

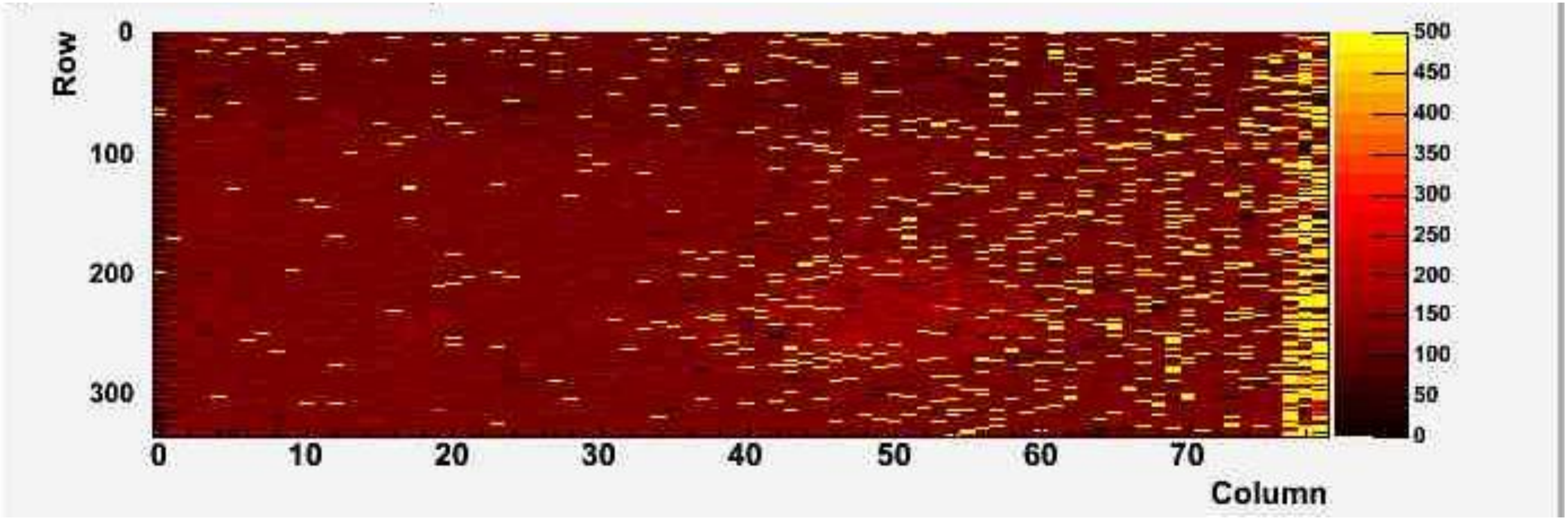
- Improvement of 1% per 1000e reduction of threshold for unirr. and irr. (centre) area
- Even more for higher irradiated ring



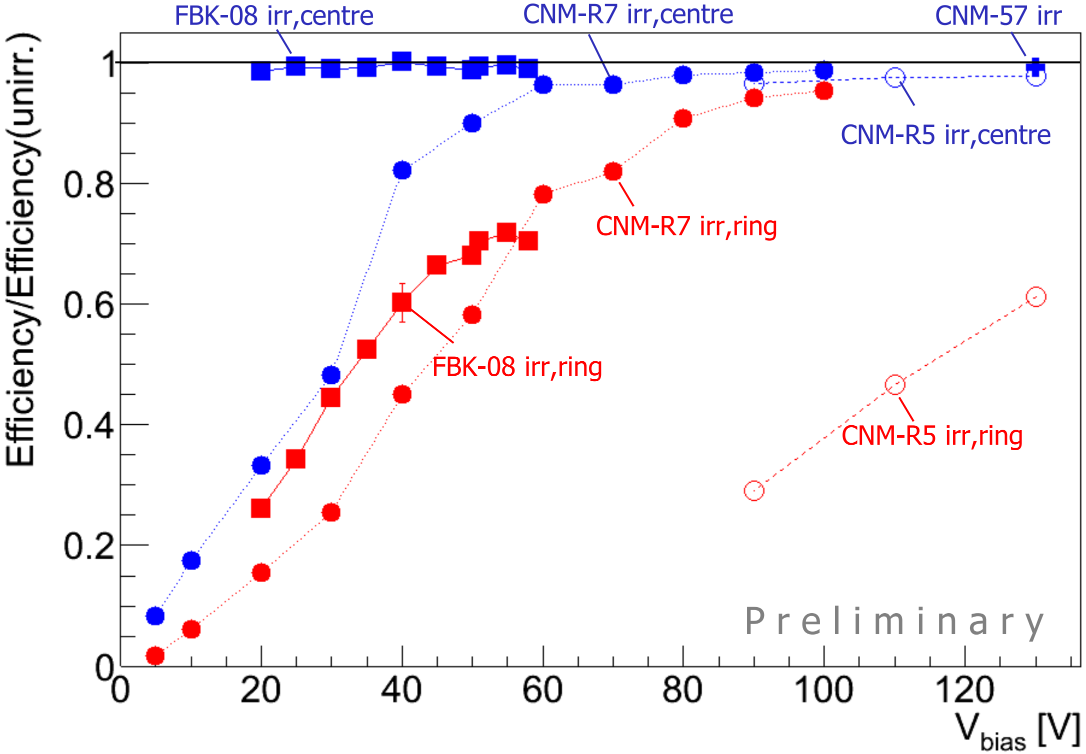
Noise of irradiated sensor

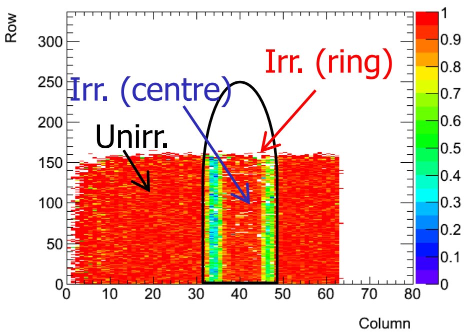
- Noise outside irradiated region ~ 130 e
- Noise inside irradiated region slightly higher (by about 10-20e)

FBK-12-02-08, 50 V



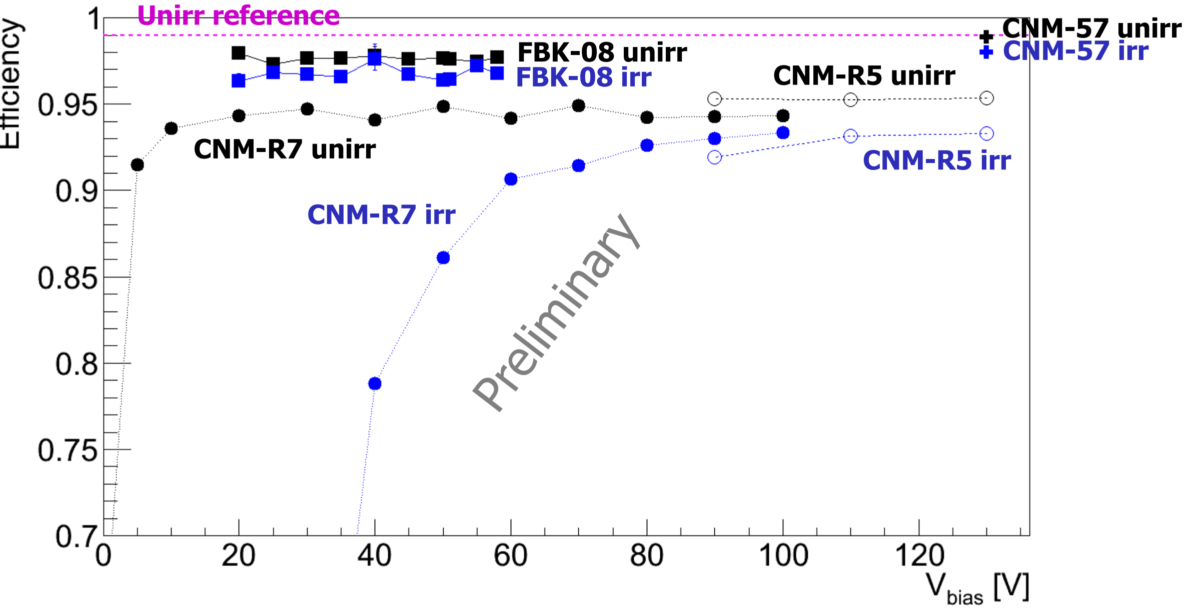
Efficiency/Efficiency(unirr.)





- For better comparison of measurements under different conditions:
  Ratio of efficiency/efficiency(unirr)
- BUT: Curve might change for CNM-R5/7 if measured with HitDiscCnfg =0 (effect on lower eff. is larger)
- Irradiated part (centre)
  - For FBK-08 (1.8×10^{15} n_{eq}/cm^2) plateau reached already below 20V
  - For CNM-R7 (~3.3×10^{15} n_{eq}/cm^2) plateau reached at about 60 V
- Irradiated part (ring)
  - All behave differently
  - FBK seems to saturate at 50 V at ~70%
  - CNM-R7 saturates at 90-100 V at ~90%
  - CNM-R5 much lower, but still steeply increasing at 130 V (60%)

Efficiency



Non-Uniform Irradiation	Unirr. Reference	PS Focussed	KIT Hole (circ.)	KIT Hole (slit)	
Φ [10^{15} n_{eq}/cm^2]	Unirr.	4.0 (max)	1.8	3.3	3.6
Sample	CNM 55	CNM 57	FBK 12_02_08	CNM S5-R7	CNM S3-R5
Edge	Regular	Regular	Regular	Slimmed	Slimmed
Threshold [ke]	3	1.7	2	3 (2)	3
Eff_{max}(unirr) [%]	99	99	98	94 (95)	94
Eff_{max}(irr) [%]	-	98	97	93 (94)	93

- Irradiated area (centre) almost as efficient as unirrad. area
- Irradiation through hole (KIT): offset for CNM devices
  - Both unirr. and irr. area
  - Note different fluence, irr. area, threshold, edge
  - Threshold of 2 ke gives 1% more
  - Problem with tuning? Non-uniform eff. even in unirr. Area
- For all devices: eff. ≥ 93%
- Highest eff. for focussed-beam irradiation with CNM-57: 98% in irr. area
- Possibly improvable by tilting sensor (15° under study)